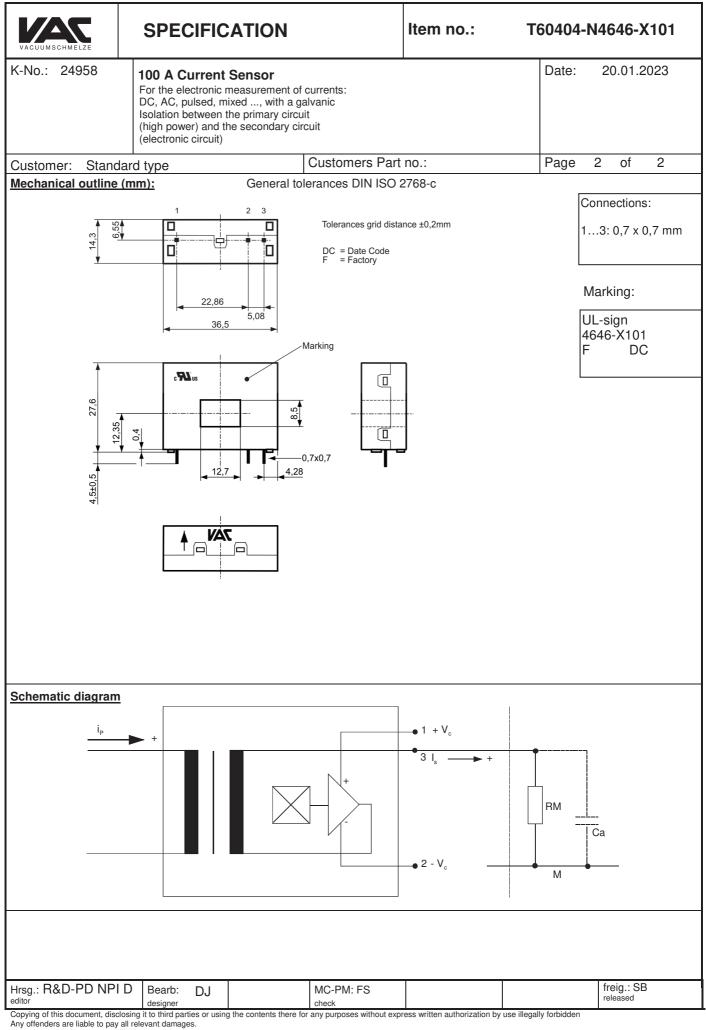
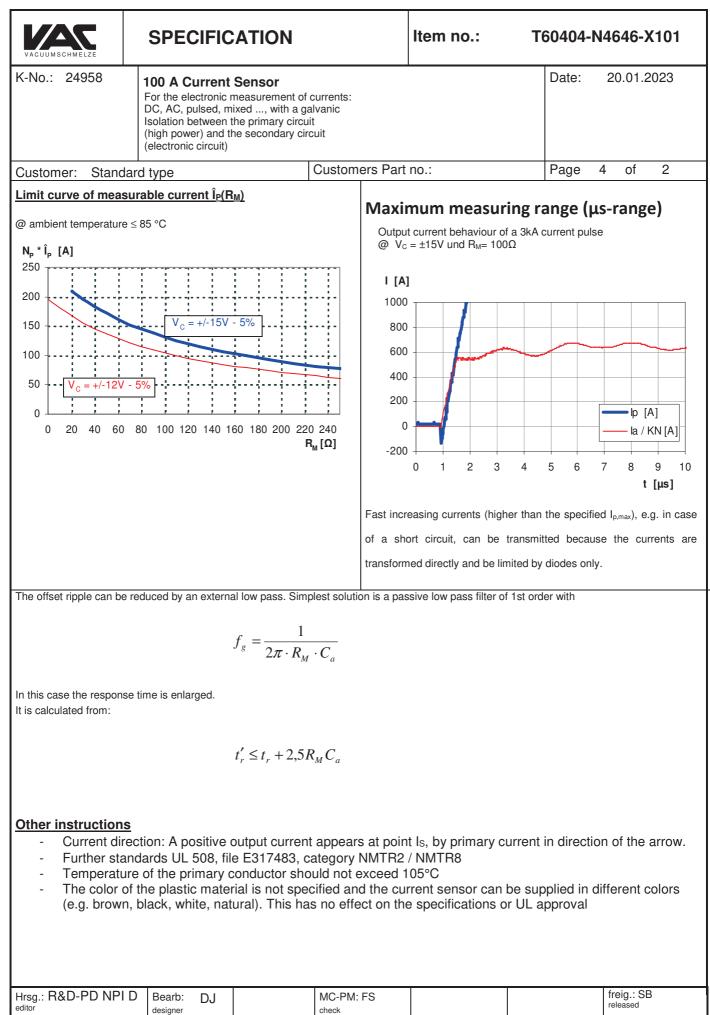
VACUUMSCHMELZE	SPECIFICATION	Item no.	.: T60404-N	Г60404-N4646-X101	
K-No.: 24958	100 A Current Sensor For the electronic measurement of currents: DC, AC, pulsed, mixed, with a galvanic Isolation between the primary circuit (high power) and the secondary circuit (electronic circuit)	Date:	20.01.2023		
Customer: Stand	dard type Customer	s Part no.:	Page	1 of 2	
 Description Closed loop (compa Current Sensor with field probe Printed circuit board Casing and materia 	Characteristics ensation) • Excellent accuracy n magnetic • Very low offset current • Very low temperature dependen current drift	Main appli cy and offset rent • •	cations: AC variabel speed drives drives Static converters for for D Battery supplied applicatic Switched Mode Power Su	tionary operation in industrial peed drives and servo motor ters for for DC motor drives ied applications de Power Supplies (SMPS) es for welding applications	
Electrical data – Ra	atings				
IPN	Primary nominal r.m.s. current		100	А	
Rм	Measuring resistance $V_{C}=\pm 12V$		0 200	Ω	
	Vc=± 15V		5 400	Ω	
Isn	Secondary nominal r.m.s. current		50	mA	
KN	Turns ratio		1:2000		
	iic performance data	min.	typ. max.	Unit	
IP,max	Max. measuring range @ V _C = $\pm 12V$, R _M = 5 Ω (t _{max} = 10sec) @ V _C = $\pm 15V$, R _M = 5 Ω (t _{max} = 10sec)	±188 ±236		A A	
Х	Accuracy @ I _{PN} , T _A = 25°C		0.1 0.5	%	
EL	Linearity		0.1	%	
lo +	Offset current @ I _P =0, T _A = 25°C		0.02 0.05	mA	
tr Δt (I _{P,max})	Response time Delay time at di/dt = 100 A/μs		200	μs ns	
f	Frequency bandwidth	DC200	200	kHz	
General data		min.	typ. max.	Unit	
TA	Ambient operating temperature	-40	+85	°C	
Ts	Ambient storage temperature	-40	+90	°C	
m	Mass		15	g	
Vc	Supply voltage	±11.4	±12 or ±15 ±15.75	V	
lc	Current consumption Constructed and manufactored and tested in Reinforced insulation, Insulation material gro			mA /s. secondary)	
Sclear	Clearance (component without solder pad)	12	, -	mm	
Screep	Creepage (component without solder pad)	12		mm	
V _{sys} V _{work}	System voltage overvoltage category 3 Working voltage (table 7 acc. to EN61800-5-	RMS	600	V	
	over voltage category 2	RMS	1000	V	
Upd	Rated discharge voltage	peak value	1225	V	
•	fference acc to UL 508	RMS	600	V	
<u>Maximale Dauer- u</u>	nd Spitzenströme bei bestimmten Temperat	<u>uren</u>			
Supply voltage ±12	V: Supp	bly voltage ±15V:			
T _A 85 °C	85 °C 70 °C 55 °C T _A	<u>85 °C</u> 85	°C 70 °C 55 °C		
IP 100 A	125 A 150 A 150 A IP	100 A 125			
I _{P,max} 188 A	183 A 185 A 194 A IP,m				
	5Ω <u>5Ω</u> 5Ω R _M	<mark>5Ω</mark> 20)Ω <mark>5Ω</mark> 5Ω		
R _M 5 Ω					
R _M 5 Ω Date Name	suue Amendment				
R _M 5 ΩDateName	81 Other instructions on sheet 4 changed. The co	blor of the plastic mate	erial added. Mechanical	outline changed	
R _M 5 Ω Date Name	81 Other instructions on sheet 4 changed. The co (size 4,28 added). Minor change		erial added. Mechanical (outline changed	



K-No.: 24958		SPECIFICATION		Item no.:		T60404-N4646-X101		
	Io.: 24958 100 A Current Sensor For the electronic measurement of currents: DC, AC, pulsed, mixed, with a galvanic Isolation between the primary circuit (high power) and the secondary circuit (electronic circuit)					Date: 20.01.2023		
Customer: Star	idard type		Customers Pa	rt no.:		Page	3 of	2
lectrical Data (in	vootigete by e	tumo chocking)						
Electrical Data (in	vestigate by a	type checking)		min.	typ.	max.	Unit	
V _{Ctot}		supply voltage (witho ±18 V: for 1s per hou				±18	V	
Rs		coil resistance @ T				114	Ω	
Хті	Temperatu	re drift of X @ $T_A = -$	-40 +85 °C			0.1	%	
loges	Offset curr	ent (including Io, Iot,	Іот)			0.07	mA	_
lot	Č.	drift Offset current la			0.025		mA	
Іот		ent temperature drif			0.025		mA	_
Іон		current @ I _P =0 (caus	ed by primary curren	t 10 x I _{PN})	0.025	0.05	mA	
$\Delta I_0 / \Delta V_C$		tage rejection ratio	с			0.01	mA/V	
loss		le (with1 MHz- filter			0.005	0,17	mA	
:	Unset ripp	le (with 100 kHz- filte	er iirst order)		0.025	0.05	mA	
i _{oss}		lo (with 00 kl - files	(first order)		0 000	0.010		
i _{oss} i _{oss} C _k	Offset ripp	le (with 20 kHz- filter possible coupling ca		econdary)	0.008	0.013	pF	
loss C _k	Offset ripp Maximum	possible coupling ca	pacity (primary – s			0.013		
loss Ck nspection (Measu	Offset ripp Maximum	possible coupling ca	pacity (primary – s e samples at room te	emperature)			pF	
nspection (Measured Kn(N1/N2) (V)	Offset ripp Maximum Irement after tem M3011/6	possible coupling ca perature balance of th Transformation ra	pacity (primary – s e samples at room te	emperature)		1 : 2000 ± 0,	pF	
loss Ck nspection (Measu	Offset ripp Maximum urement after tem M3011/6 M3226	possible coupling ca perature balance of th Transformation ra Offset current Test voltage, rms,	e samples at room te tio (IP=100A, 40-80	emperature)			pF	
Ioss Сk КN(N1/N2) (V) Io (V) Vd (V)	Offset ripp Maximum Irement after tem M3011/6 M3226 M3014:	possible coupling ca perature balance of th Transformation ra Offset current Test voltage, rms, pin 1 – 3 vs. hole	e samples at room te tio (IP=100A, 40-80 1 s	emperature) I Hz)		1 : 2000 ± 0, < 0.05 1.8	pF 5% mA kV	
Ioss Ck Ck (Measu KN(N1/N2) (V) Io (V) Vd (V) Ve (A)	Offset ripp Maximum Maximum M3011/6 M3226 M3014: AQL 1/S4)	possible coupling ca perature balance of th Transformation ra Offset current Test voltage, rms,	e samples at room te tio (IP=100A, 40-80 1 s	emperature) I Hz)		1 : 2000 ± 0, < 0.05	pF ,5 % mA	
Ioss Ck KN(N1/N2) (V) Io (V) Vd (V) Ve (A Ve (A	Offset ripp Maximum M3011/6 M3226 M3014: AQL 1/S4) 1 - 3 to hole)	possible coupling ca perature balance of th Transformation ra Offset current Test voltage, rms, pin 1 – 3 vs. hole Partial discharge v with V _{vor} (RMS)	e samples at room te tio (IP=100A, 40-80 1 s voltage acc.M3024	emperature) 9 Hz) (RMS)	6	1 : 2000 ± 0, < 0.05 1.8 1300 1625	pF 	
Ioss Ck Ck (Measu KN(N1/N2) (V) Io (V) Vd (V) Ve (A Vype Testing (Pin Vw (Pin	Offset ripp Maximum Maximum M3011/6 M3226 M3014: AQL 1/S4) 1 - 3 to hole) HV transie	possible coupling ca perature balance of th Transformation ra Offset current Test voltage, rms, pin 1 – 3 vs. hole Partial discharge v with V _{vor} (RMS)	e samples at room te tio (IP=100A, 40-80 1 s voltage acc.M3024	emperature) 9 Hz) (RMS)	6 	1 : 2000 ± 0. < 0.05 1.8 1300 1625 8	pF mA kV V V	
Ioss Сk КN(N1/N2) (V) Io (V) Vd (V) Ve (A Cype Testing (Pin	Offset ripp Maximum Maximum M3011/6 M3226 M3014: AQL 1/S4) 1 - 3 to hole) HV transie Testing vo	possible coupling ca perature balance of th Transformation ra Offset current Test voltage, rms, pin 1 – 3 vs. hole Partial discharge v with V _{vor} (RMS)	e samples at room te tio (IP=100A, 40-80 1 s voltage acc.M3024 M3064 (1,2 μs / 50	emperature) 9 Hz) (RMS)	6	1 : 2000 ± 0, < 0.05 1.8 1300 1625	pF 	



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VACUUMSC	IMELZE	SPECIFIC	ATION	Item no.:	T60404-N4646-X101
K-No.: 2	24958		neasurement of currents xed, with a galvanic ne primary circuit	:	Date: 20.01.2023
Custome	r: Standa	ard type	Custo	mers Part no.:	Page 5 of 2
Explanati	on of seve	ral of the terms use	ed in the tablets (in a	alphabetical order)	·
loн: lot:			-	d the rated value ($R_M = R_{MN}$ n the range -40 bis 85 °C.	u)
tr:	Respons	e time, measured as	s delay time at $I_P = 0.8$	B · IPmax between a rectang	ular current and the output current.
$\Delta t (I_{Pmax}):$	Delay tin	ne between I _{Pmax} and	I the output current ia	with a primary current rise o	of $di_1/dt = 100 \text{ A}/\mu \text{s}.$
U _{PD}	Rated disc UPD	harge voltage (recur = $\sqrt{2} * V_e / 1,5$	ring peak voltage sep	parated by the insulation) pr	oved with a sinusoidal voltage $V_{\mbox{\scriptsize e}}$
Vvor	Defined vo test in IEC V _{vor}		ve of a sinusoidal vol	tage with peak value of 1,87	75 * UPD required for partial discharge
Vsys	System vo	ltage RMS value	e of rated voltage acco	ording to IEC 61800-5-1	
Vwork	Working vo	oltage voltage acc	ording to IEC 61800-	5-1 which occurs by design	in a circuit or across insulation
X _{ges} (I _{PN}):		of all possible errors $00 \cdot \left \frac{I_{s}(I_{PN})}{K_{N} \cdot I_{SN}} - 1 \right $	s over the temperatur	e range by measuring a cur	rent I _{PN} :
X:	Permissi	ble measurement er	ror in the final inspect	ion at RT, defined by	
	X =10	$0 \cdot \left \frac{I_{SB}}{I_{SN}} - 1 \right $			
	where Ise	₃ is the output DC va	llue of an input DC cu	rrent of the same magnitud	e as the (positive) rated current ($I_0 = 0$
X _{Ti} :	Tempera obtained		value orientated out	out term. I_{SN} (cf. Notes on F	i) in a specified temperature range,
	$X_{\mathrm{Ti}} = 1$	$100 \cdot \left \frac{\mathrm{I}_{\mathrm{SB}}(\mathrm{T}_{\mathrm{A2}}) - \mathrm{I}_{\mathrm{SN}}}{\mathrm{I}_{\mathrm{SN}}} \right $	$\frac{I_{SB}(T_{A1})}{T_{A1}}$		
EL:	Linearity	fault defined by	$\varepsilon_{\rm L} = 100 \cdot \left \frac{\rm I_{\rm p}}{\rm I_{\rm pN}} - \frac{\rm I}{\rm I_{\rm pN}} \right $	Sx	
	Where I _P			sn g output term. I _{SN} : see notes	s of F_i ($I_o = 0$).
	D-PD NPI	D Bearb: DJ	MC-PI	M: FS	freig.: SB
editor		designer	check		released